

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. GIVAR7.0016SC	APPLICATION NO. 09/880,432
	APPLICANT Givargizov, et al.	
	FILING DATE November 28, 2001	GROUP Unknown

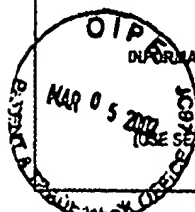
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
EN	5,742,377	04/21/88	Ména, et al.	—	—	
EN	5,825,122	10/20/99	Givargizov, et al.	—	—	
EN	6,308,734	10/23/01	Givargizov	—	—	

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
EN	WO 88/42101	12/27/88	PCT	—	—		
EN	WO 89/58825	11/18/89	PCT	—	—		

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
EN	C.A. Spindt et al., Physical properties of thin-film field emission cathodes with molybdenum cores, J. Appl. Phys., 47, pp. 5248-5283 (1976)
EN	P. Grütter, et al., Batch fabricated sensors for magnetic force microscopy, Appl. Phys. Lett. 57, pp. 1820-1822 (1990)
EN	D.W. Abraham, et al., Lateral dopant profiling in semiconductors by force microscopy using capacitive detection, J. Vac. Sci. Technol., 89, pp. 703-708 (1991)
EN	K.L. Lee, et al., Submicron Si trench profiling with an electron-beam fabricated atomic force microscope tip, J. Vac. Sci. Technol., 89, pp. 3352-3368 (1991)
EN	E.I. Givargizov, Ultrasharp tips for field emission applications prepared by the vapor-liquid-solid growth technique, J. Vac. Sci. Technol., B11, pp. 449-453 (1993)

EXAMINER	K. NGUYEN	DATE CONSIDERED	02-24-05
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 808; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. GVAR7.001APC	APPLICATION NO. 09/660,432
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Givargizov, et al.	
		FILING DATE November 29, 2001	GROUP Unknown



EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
GV	C.D. Frisbie, et al., <i>Functional group imaging by chemical force microscopy</i> , Science, 265, pp. 2071-2074 (1994)
	V.A. Bykov, et al., <i>New devices and possibilities in a scanning probe microscopy</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhni Novgorod, pp. 132-133 (March 1999)
	J. Browning, <i>Field emission display development and testing</i> , Proc. Of the 8th Intern. Conf. On Vacuum Microelectronics (Portland, USA), pp. 1-6 (1995)
	Y. Huang, et al., <i>Quantitative two-dimensional dopant profiling of abrupt dopant profiles by cross-sectional scanning capacitance microscopy</i> , J. Vac. Sci. Technol. A14, pp. 1168-1171 (1996)
	J.M. Hamner, et al., <i>Growth of nanotubes for probe microscopy tips</i> , Nature 358, pp. 781-782 (1999)
	P. Lehenbach, et al., <i>Fabrication and characterization of advanced probes for magnetic force microscopy</i> , Appl. Surf. Sci., 144-145, pp. 492-498 (1998)
	L. Abelman, et al., <i>Analysis of the limit of resolution in magnetic force microscopy using EBID tips</i> , a paper presented to Intern. STM Conf., Seoul, Korea, Ext. Abstr., pp. 477-478 (1998)
	V.V. Dronov, et al., <i>An alternative working mode of SPM at surface investigations</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhni Novgorod, pp. 404-410 (March 1999)
GV	E.I. Givargizov, et al., <i>Whisker probes</i> , Ultramicroscopy 82, pp. 57-61 (2000)

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EXAMINER	K. NOV 4GV	DATE CONSIDERED	02-24-05
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